

Supplementary: Attosecond stable dispersion-free delay line for easy ultrafast metrology

Akansha Tyagi¹, Mehar S. Sidhu¹, Ankur Mandal¹, Sanjay Kapoor¹, Sunil Dahiya¹, Jan M. Rost², Thomas Pfeifer³, Kamal P. Singh¹

*Department of Physical Sciences, Indian Institute of Science Education and Research
Mohali, Sector 81, Manauli 140306, India.*

Max Planck Institute for Physics of Complex Systems, Dresden, Germany

Max Planck Institute for Nuclear Physics, Heidelberg, Germany

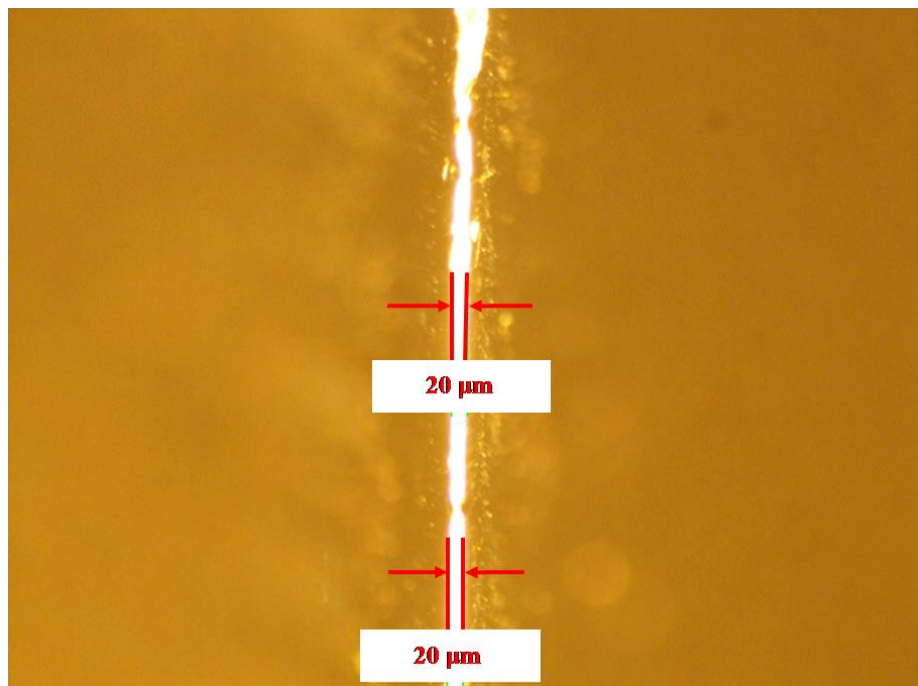


Figure S1: Optical microscopic image of reflective beam splitting knife edge prism used in all reflective delay line, showing knife edge sharpness of the order of $\approx 20 \mu\text{m}$

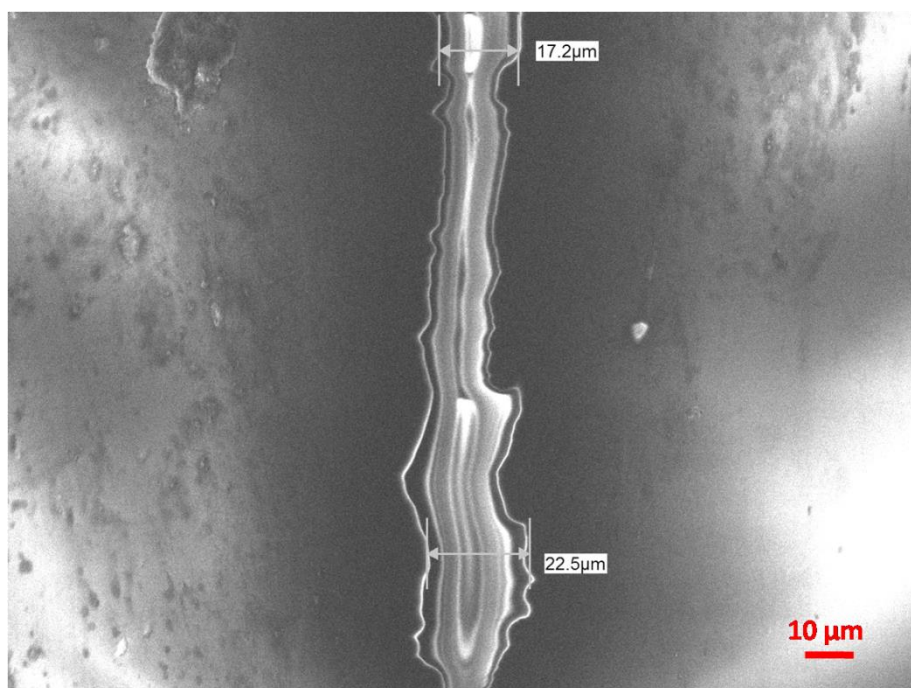


Figure S2: Electron microscopic image of reflective beam splitting knife edge prism